

**Search Notes**

Application/Control No.

10/810,574

Examiner

Hau V. Phan

Applicant(s)/Patent under  
Reexamination

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Art Unit

3618

**SEARCHED**

Class	Subclass	Date	Examiner
280	163 164.1 164.2	8/12/2006	HP
	759		
	782		
	830		
239	284.1	8/12/2006	HP
	106		
296	193.12	8/12/2006	HP
15	250.02	8/12/2006	HP
429	100	8/12/2006	HP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text Search	8/12/2006	HP